

Assessment of power density of human exposure to radio frequency fields from wireless devices in close proximity to the head and body (frequency range of 6 GHz to 300 GHz) - Part 2: Computational procedure

EESTI STANDARDI EESSÕNA

NATIONAL FOREWORD

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English Version

Assessment of power density of human exposure to radio frequency fields from wireless devices in close proximity to the head and body (frequency range of 6 GHz to 300 GHz) - Part 2:
Computational procedure
(IEC/IEEE 63195-2:2022)

Évaluation de la densité de puissance de l'exposition humaine aux champs radiofréquences provenant de dispositifs sans fil à proximité immédiate de la tête et du corps (plage de fréquences de 6 GHz à 300 GHz) - Partie 2: Procédure de calcul
(IEC/IEEE 63195-2:2022)

Bewertung der Leistungsdichte der Exposition des Menschen gegenüber hochfrequenten Feldern von drahtlosen Geräten in unmittelbarer Nähe des Kopfes und des Körpers (Frequenzbereich von 6 GHz bis 300 GHz) - Teil 2: Berechnungsverfahren
(IEC/IEEE 63195-2:2022)

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European foreword

This document (EN IEC/IEEE 63195-2:2023) consists of the text of document IEC/IEEE 63195-2:2022, prepared by IEC/TC 106 "Methods for the assessment of electric, magnetic and electromagnetic fields associated with human exposure".

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IEC/IEEE 62209-1528:2020 NOTE Harmonized as EN IEC/IEEE 62209-1528:2021 (not modified)

Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

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<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC/IEEE 62704-1	2017	Determining the peak spatial-average specific absorption rate (SAR) in the human body from wireless communications devices, 30 MHz to 6 GHz - Part 1: General requirements for using the finite difference time-domain (FDTD) method for SAR calculations	-	-
IEC/IEEE 62704-4	2020	Determining the peak spatial-average specific absorption rate (SAR) in the human body from wireless communication devices, 30 MHz to 6 GHz - Part 4: General requirements for using the finite element method for SAR calculations	-	-
IEC/IEEE 63195-1	2022	Assessment of power density of human exposure to radio frequency fields from wireless devices in close proximity to the head and body (frequency range of 6 GHz to 300 GHz) - Part 1: Measurement procedure	EN IEC/IEEE 63195-1	2023
IEEE 145	-	Definitions of terms for antennas	-	-



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Assessment of power density of human exposure to radio frequency fields from wireless devices in close proximity to the head and body (frequency range of 6 GHz to 300 GHz) –

Part 2: Computational procedure

Évaluation de la densité de puissance de l'exposition humaine aux champs radiofréquences provenant de dispositifs sans fil à proximité immédiate de la tête et du corps (plage de fréquences de 6 GHz à 300 GHz) –

Partie 2: Procédure de calcul



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INTERNATIONAL STANDARD

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Part 2: Computational procedure**

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Partie 2: Procédure de calcul**

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

**ASSESSMENT OF POWER DENSITY OF HUMAN EXPOSURE TO RADIO
FREQUENCY FIELDS FROM WIRELESS DEVICES IN CLOSE PROXIMITY
TO THE HEAD AND BODY (FREQUENCY RANGE OF 6 GHz TO 300 GHz) –****Part 2: Computational procedure**

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IEC/IEEE 63195-2 was prepared by IEC technical committee 106: Methods for the assessment of electric, magnetic and electromagnetic fields associated with human exposure, in cooperation with the International Committee on Electromagnetic Safety (ICES) of the IEEE Standards Association, under the IEC/IEEE Dual Logo Agreement between IEC and IEEE. It is an International Standard.

This document is published as an IEC/IEEE Dual Logo standard.

This publication contains supplemental files that are required for the code verification according to Annex A. Download links and checksums for these files can be found in Annex I.

The text of this International Standard is based on the following IEC documents:

Draft	Report on voting
106/564/FDIS	106/569/RVD

Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this International Standard is English.

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A list of all parts in the IEC/IEEE 63195 series, published under the general title *Assessment of power density of human exposure to radio frequency fields from wireless devices in close proximity to the head and body*, can be found on the IEC website.

The IEC Technical Committee and IEEE Technical Committee have decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under webstore.iec.ch in the data related to the specific document. At this date, the document will be

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INTRODUCTION

This document provides a method to evaluate the human exposure from wireless devices using computational methods. This document was developed to provide procedures for the numerical modelling and evaluation of such wireless devices operating close to the head, held in the hand or in front of the face, mounted on the body or embedded in garments. It applies to individual transmitters as well as to transmitters operating simultaneously with other transmitters within a product. The choice of technique, i.e. FDTD or FEM, is optional but can be influenced by the application. The advantages of computational procedures include the capability to provide repeatable, non-intrusive methods for determining exposure in or near an object and without the need for expensive hardware equipment. Device categories covered include but are not limited to mobile telephones, radio transmitters in personal computers, desktop and laptop devices, and multi-band and multi-antenna devices. This document specifies:

- requirements on the numerical software (Clause 5);
- model development and validation (Clause 7);
- power density computation and averaging (Clause 8);
- uncertainty evaluation (Clause 9);
- reporting requirements (Clause 10).

To develop this document, IEC Technical Committee 106 (TC 106) and IEEE International Committee on Electromagnetic Safety (ICES), Technical Committee 34 (TC 34) Subcommittee 1 (SC 1) formed Joint Working Group 11 (JWG 11) on computational methods to assess the power density of human exposure to radio frequency fields from wireless devices in close proximity to the head and body.

ASSESSMENT OF POWER DENSITY OF HUMAN EXPOSURE TO RADIO FREQUENCY FIELDS FROM WIRELESS DEVICES IN CLOSE PROXIMITY TO THE HEAD AND BODY (FREQUENCY RANGE OF 6 GHz TO 300 GHz) –

Part 2: Computational procedure

1 Scope

This document specifies computational procedures for conservative and reproducible computations of power density (PD) incident to a human head or body due to radio-frequency (RF) electromagnetic field (EMF) transmitting devices. The computational procedures described are finite-difference time-domain (FDTD) and finite element methods (FEM), which are computational techniques that can be used to determine electromagnetic quantities by solving Maxwell's equations within a specified computational uncertainty. The procedures specified here apply to exposure evaluations for a significant majority of the population during the use of hand-held and body-worn RF transmitting devices. The methods apply to devices that can feature single or multiple transmitters or antennas, and that can be operated with their radiating part or parts at distances up to 200 mm from a human head or body.

This document can be employed to determine conformity with any applicable maximum PD requirements of different types of RF transmitting devices used in close proximity to the head and body, including those combined with other RF transmitting or non-transmitting devices or accessories (e.g. belt-clip), or embedded in garments. The overall applicable frequency range of these protocols and procedures is from 6 GHz to 300 GHz.

The RF transmitting device categories covered in this document include but are not limited to mobile telephones, radio transmitters in personal computers, desktop and laptop devices, and multi-band and multi-antenna devices.

The procedures of this document do not apply to PD evaluation of electromagnetic fields emitted or altered by devices or objects intended to be implanted in the body.

NOTE For the evaluation of the combined exposure from simultaneous transmitters operating on frequencies below 6 GHz, the relevant standards for SAR computation are IEC/IEEE 62704-1:2017 and IEC/IEEE 62704-4:2020.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC/IEEE 62704-1:2017, *Determining the peak spatial-average specific absorption rate (SAR) in the human body from wireless communications devices, 30 MHz to 6 GHz – Part 1: General requirements for using the finite difference time-domain (FDTD) method for SAR calculations*

IEC/IEEE 62704-4:2020, *Determining the peak spatial-average specific absorption rate (SAR) in the human body from wireless communications devices, 30 MHz to 6 GHz – Part 4: General requirements for using the finite element method for SAR calculations*

IEC/IEEE 63195-1:2021¹, *Assessment of power density of human exposure to radio frequency fields from wireless devices in close proximity to the head and body (frequency range of 6 GHz to 300 GHz) – Part 1: Measurement procedure*

IEEE Std 145, *IEEE Standard for Definitions of Terms for Antennas*

3 Terms and definitions

For the purposes of this document, the following terms and definitions apply.

ISO, IEC, and IEEE maintain terminological databases for use in standardization at the following addresses:

- IEC Electropedia: available at <http://www.electropedia.org/>
- ISO Online browsing platform: available at <http://www.iso.org/obp>
- IEEE Dictionary Online: available at <http://dictionary.ieee.org>

3.1 Exposure metrics and parameters

3.1.1

power density

PD

local power density

function of the complex Poynting vector S at the location r that is integrated over a surface to compute the sPD

Note 1 to entry: Specifications of power density in terms of the integrands of Formula (4), Formula (5), and Formula (8) are provided in 8.5. See also rationales provided in Annex F for the PD specifications of 8.5.

Note 2 to entry: The formula used to compute PD can depend on the applicable exposure guidelines or national regulations.

Note 3 to entry: Power density is also referred to as power flux density.

Note 4 to entry: The associated term incident power density refers to quantity of power per unit area that impinges on the body surface. The incident power density just outside the body surface is used to establish local exposure reference levels, which apply at frequencies above 6 GHz in some jurisdictions.

3.1.2

spatial-average power density

sPD

PD (3.1.1) averaged over a surface of area A_{av}

Note 1 to entry: sPD is a function of the location vector r . It is determined on the evaluation surface, except for the edges where no averaging area can be constructed.

Note 2 to entry: Example averaging area sizes specified in exposure limits are 1 cm² and/or 4 cm².

¹ To be published.